



**12500 TI Boulevard, MS 8640, Dallas, Texas 75243**

**Qualification Report for PCN# 20120418002  
4H CBC10 from HFAB to SFAB  
Information Only**

Dear Customer:

This is to inform you of the completion of qualification testing for the product change described in PCN# 20120418002. The details of the qualification results are included in the following pages and are being forwarded to you in response to your inquiry about this PCN.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager ([PCN ww admin team@list.ti.com](mailto:PCN_admin_team@list.ti.com)).

Sincerely,

PCN Team  
SC Business Services  
Phone: +1(214) 480-6037  
Fax: +1(214) 480-6659

## Qualification Report For # 20120418002

### 4H CBC10 from HFAB to SFAB

#### Qualification Data:

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.

Attributes	Qual Device: LOG114A IRGV	Qual Device: OPA267 3IRGV	Qual Device: OPA468 4ID	Qual Device: OPA487 2ID	Qual Device: OPA657 UB	Qual Device: OPA846	Qual Device: OPA890I D	QBS Process: OPA267 4ID	QBS Process: OPA487 2ID	QBS Process: OPA890I D
Assembly Site	CRS-CARSEM	MLA	MLA	MLA	MLA	MLA	MLA	MLA	MLA	MLA
Package Family	VQFN	VQFN	SOIC	SOIC	SOIC	SOIC	SOIC	SOIC	SOIC	SOIC
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0
Wafer Fab Supplier	SFAB	SFAB	SFAB	SFAB	SFAB	SFAB	SFAB	HFAB/SFAB	HFAB/SFAB	HFAB/SFAB
Wafer Fab Process	CBC10	CBC10	CBC10	CBC10	CBC10	CBC10	CBC10	CBC10	CBC10	CBC10

#### Qualification Results

Data Displayed as: Number of lots/ Total Sample Size/ Total Failed

Type	Test Name / Condition	Duration	Qual Device: LOG114AIRGV	Qual Device: OPA2673IRGV	Qual Device: OPA4684ID	Qual Device: OPA4872ID	Qual Device: OPA657UB	Qual Device: OPA846	Qual Device: OPA890ID	QBS Process: OPA2674ID	QBS Process: OPA4872ID	QBS Process: OPA890ID
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	-	1/77/0	1/80/0	-	1/80/0	1/87/0	1/82/0	1/84/0
AC	Autoclave 121C	96 Hours	-	-	-	-	-	-	-	-	1/87/0	1/87/0
UHAST	Unbiased HAST 130C/85%RH	96 Hours	-	-	-	1/80/0	1/80/0	-	1/80/0	-	-	-
TC	Temperature Cycle, -65/150C	500 Cycles	-	-	-	1/79/0	1/80/0	-	1/80/0	-	1/87/0	1/87/0
HTSL	High Temp. Storage Bake, 150C	1000 Hours	-	-	-	1/80/0	1/80/0	-	1/80/0	-	1/87/0	1/87/0
HTOL	Life Test, 125C	1000 Hours	1/77/0	1/80/0	-	1/80/0	1/80/0	-	1/80/0	-	1/87/0	-
WBS	Shear	Wires	-	-	-	-	-	-	-	-	1/76/0	-
HBM	ESD - HBM	1000 V	-	1/3/2000	-	1/6/2000	1/3/2000	-	1/3/2000	-	1/3/2000	1/3/2000
CDM	ESD - CDM	250V	-	1/3/2000	-	1/3/2000	1/3/2000	-	1/3/2000	-	-	-
LU	Latch-up (per JESD78)		-	-	-	-	1/6/2000	-	1/6/2000	-	-	-
ED	Electrical Characterization	Per Datasheet Parameters	Pass	Pass	Pass	Pass	Pass	-	-	-	Pass	Pass
	Bond Strength	Wires	-	-	-	-	-	-	-	-	1/76/0	-

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	<a href="mailto:PCNAmericasContact@list.ti.com">PCNAmericasContact@list.ti.com</a>
Europe	<a href="mailto:PCNEuropeContact@list.ti.com">PCNEuropeContact@list.ti.com</a>
Asia Pacific	<a href="mailto:PCNAsiaContact@list.ti.com">PCNAsiaContact@list.ti.com</a>
Japan	<a href="mailto:PCNJapanContact@list.ti.com">PCNJapanContact@list.ti.com</a>